BS QC 160101:1987 IEC 255-19-1: 1983

**Specification for** 

Harmonized system of quality assessment for electronic components — Electrical relays — Blank detail specification —

Electromechanical all-or-nothing relays — Test schedules 1, 2 and 3



## Amendments issued since publication

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# National foreword

This British Standard has been prepared under the direction of the Electronic Components Standards Committee. It is identical with IEC Publication 255-19-1 (QC 160101) "Electrical relays — Part 19: Blank detail specification: Electromechanical all-or-nothing relays of assessed quality. Test schedules 1, 2 and 3", published in 1983 by the International Electrotechnical Commission (IEC).

This standard is a harmonized specification within the IECQ system of quality assessment for electronic components.

**Terminology and conventions.** The text of the International Standard has been approved as suitable for publication as a British Standard without deviation. Some terminology and certain conventions are not identical with those used in British Standards; attention is drawn especially to the following.

#### **Cross-references**

International Standards*	Corresponding British Standards
	BS 2011 Basic environmental testing procedures
IEC 68-1:1982	Part 1.1:1983 General and guidance
	(Identical)
IEC 68-2-10:1984	Part 2.1J:1985 Test J. Mould growth
	(Identical)
	BS 5992 Electrical relays
IEC 255-0-20:1974	Part 1:1980 Specification for contact performance of electrical relays
	(Identical)
IEC 255-1-00:1975	Part 2:1980 Specification for all-or-nothing relays (Identical)
	BS QC 160000 Harmonized system of quality assessment for electronic components.
	Electrical relays. Generic specification:
	Electromechanical all-or-nothing relays
IEC 255-7:1978	Part 1:1987 Test and measurement procedures
	(Identical)
IEC 255-10:1979	Part 2:1987 Quality assessment procedures
	(Identical)
IEC 255-19:1983 (QC 160100)	BS QC 160100:1987 Harmonized system of quality assessment for electronic components. Electrical relays. Sectional specification:
	Electromechanical all-or-nothing relays
	(Identical)
IEC 443:1974	BS 5148:1975 Method for specifying the performance of stabilized power supply apparatus (Technically equivalent)
ISO 2015:1976	BS 4760:1971 Specification for numbering of weeks (Technically equivalent)

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A British Standard does not purport to include all the necessary provisions of a contract. Users of British Standards are responsible for their correct application.

Compliance with a British Standard does not of itself confer immunity from legal obligations.

## Summary of pages

This document comprises a front cover, an inside front cover, pages i to iv, pages 1 to 30 and a back cover.

This standard has been updated (see copyright date) and may have had amendments incorporated. This will be indicated in the amendment table on the inside front cover.

iv blank

#### Section 1. General

#### 1 Scope

This blank detail specification applies to electromechanical all-or-nothing relays, test schedules 1, 2 and 3 of assessed quality.

#### 2 Object

This blank detail specification gives the tests to be used and the layout to be followed when preparing detail specifications for electromechanical all-or-nothing relays. The test schedules are defined, and the relationship to each other is described in the sectional specification for such relays in IEC Publication 255-19 which selects appropriate tests from IEC Publication 255-7 in accordance with IEC Publication 255-10.

#### 3 Related documents

IEC Publication 68-1, Basic Environmental Testing Procedures — Part 1: General and Guidance.

IEC Publication 255-7, Electrical Relays — Part 7: Test and Measurement Procedures for Electromechanical All-or-nothing Relays (Generic specification).

IEC Publication 255-10-10, Application of the IEC Quality Assessment System to All-or-nothing Relays.

IEC Publication 255-19-19, Sectional Specification for All-or-nothing Relays of Assessed Quality.

IEC Publication 443, Stabilized Supply Apparatus for Measurement.

ISO Standard 2015, Numbering of weeks.

Any document to which direct reference is needed and which is not quoted elsewhere.

## 4 Diversity of detail specifications

One detail specification shall only cover structurally similar relays (see IEC Publication 255-19).

#### 5 Identification of detail specifications

Identification of each detail specification shall be provided by an IEC number, date of issue and, regarding the test schedules, in accordance with IEC Publication 255-10.

#### 6 Test schedules in detail specifications

Test schedules shall, as a minimum, contain the tests marked as mandatory (M) in Section 2 of this specification, considering the properties of the relay concerned, its contact category, and the notes in Appendix B of IEC Publication 255-10 and Appendix A of IEC Publication 255-19. The test procedures may be extended, and tests marked as recommended (R) may be added. Tests not listed in Appendix B of IEC Publication 255-10 may be added either from, or in addition to the generic specification, and such tests may be altered if necessary, under the conditions of Clauses 7 and 8.

Any test or test procedure laid down in a detail specification shall be mandatory for the relay(s) covered by that specification.

#### 7 Non-harmonized test procedures

At the discretion of National Committees or other standards-issuing authorities, detail specifications may contain tests beyond those specified in IEC Publication 255-7 (generic specification).

Such tests shall be clearly indicated as non-harmonized and their description and layout shall follow those of the harmonized tests.

#### 8 Altered test procedures

If the technical requirements of the generic specification relative to inspection are not entirely suitable (either for technical reasons or because of special application) to the relay described in the detail specification, the latter shall set out clearly the various amendments which are to be made to these requirements.

#### 9 Quality conformance inspection

Test schedules 1, 2 and 3 for quality conformance inspection are contained in Table I, Table III and Table V respectively. The order of the tests within the sub-groups of these tables should, in general, be appropriate for their sequence when performed, but the detail specification shall specify the mandatory order considering the nature of the relays to be tested. Tests to be added to those listed in Table I, Table III and Table V shall be arranged in the suitable group and sub-group, and at the appropriate place within such sub-group.

When assigning IL- and AQL-notations, the IL values given under the heading of each sub-group shall be used, and the AQL values shall be within the given range.

#### 10 Qualification approval tests

When Method 1 of Clause 4 of IEC Publication 255-10 applies, the test schedules shall be as shown in Table II, Table IV and Table VI of the present specification and shall be consistent with that used for quality conformance inspection.

The detail specification shall also state the sample size and the associated permissible number of defectives. The entries in Table II, Table IV and Table VI indicate minimum sample sizes, taking into account that the confidence in the results of the qualification approval tests cannot only be derived from statistical considerations but should also pay regard to the overall technical information and the cost involved in the tests. A minimum sample size of five specimens per test group plus one specimen for replacement of one defective relay, i.e. acceptance on one defective relay, may be appropriate in most cases to form sample groups, while the total of all samples will be subject to some basic tests on a miss-free basis. For example in Table 11, Table 18 specimens will be required for the "all samples" test which are divided

For example in Table 11, Table 18 specimens will be required for the "all samples" test which are divided into five plus one specimens each in three sample groups.

If this minimum sample size is not deemed sufficient, sampling plans from IEC Publication 410 shall preferably be used, and the limiting quality of the sampling plan shall be considered for agreement between manufacturer and purchaser.

Other relations between the sample size and allowed number of defectives of qualification approval tests versus the criteria of quality conformance inspection may be considered and specified in the detail specification.

#### Section 2. Contents of detail specifications

#### 11 General requirements

Detail specifications shall comply with the requirements given below and the tables in them shall be completed in accordance with the entries in the tables in this specification. Where relevant, the entries should take account of Section 1 of this specification and the appropriate clauses of IEC Publications 255-7 and 255-10. It should be understood that writing a detail specification is the task of an engineer who is well aware of these specifications and of the relays he has to specify.

#### 12 Symbols

The symbols in front of the lines of the columns for conditions of test and performance requirements denote, in accordance with IEC Publications 255-7 and 255-10:

M: mandatory test

R: recommended test

M, R: as above, but see restrictions in IEC Publications 255-7 and 255-10

+: state if required ×: state if applicable

#### 13 Front page

The entries on the front page shall be as follows. The circled numbers correspond to those in the layout of Sub-clause 13.4.

#### 13.1 Identification of the detail specification

- (1) The name of the National Standards Organization under whose authority the detail specification is drafted.
- (2) The IEC number of the relevant blank detail specification.
- (3) The number and issue of the national generic specification.
- (4) The national number of the detail specification, date of issue and further information required by the national system.

#### 13.2 Identification of the component

- (5) A short description of the type of relay as necessary for its identification.
- (6) Information on its particular construction (where applicable).
- ① Outline drawing and/or reference to the relevant document for outlines. Alternatively, this drawing may be given in an appendix to the detail specification.
- (8) Application and test schedule.

NOTE The order of ranking of the test schedules is as given in Clause **A.1** of Appendix A of the sectional specification, IEC Publication 255-19.

(9) Reference data of the most important properties.

#### 13.3 Example of reference data, presentation is optional

#### Reference data

This information is not for inspection purposes.

#### 1) Coil

Coil voltage (V d.c.)	Number of turns	Resistance at 20 $^{\circ}\mathrm{C}$ $(\Omega)$	Test voltage (kV)	Coil variant code
6	545	3.1		70
12	1 090	14.7		71
24	2 180	58	2.5	72
220	20 000	5 000		78

#### 2) Contacts

Туре	Continuous contact current (A)	Open-circuit voltage (V)	Make/break power (W)	Test voltage (kV)	Contact code
1 make	15		1 000 = /2 200 ~		1A
2 make	10	440 = /		2.5	2A
1 change-over	10	380 ~			1C
2 change-over	10		600 = /1 500 ~		2C

3) Temperature range: 0 °C ... + 40 °C

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#### 13.4 Layout of the front page of detail specifications

1)	Page: Of:	IEC Issue 1	2
3			4
DETAIL SPECIFICATION FOR: ALL-OR-NOTHING TYPE(S): CONSTRUCTION:	RELAY		5
			6
(Outline drawing)	Application:		8
	Test schedule: × (	or × with additions)	
Reference data This information is not for inspection purposes.			9

#### 14 Related documents

**14.1** IEC Publication 255-7, and further publications referenced therein (state, as appropriate, further related documents).

## 15 Characteristic values

(state in accordance with IEC Publication 255-1-00)

### 16 Formation of inspection lots

(state as applicable)

#### 17 Intervals between tests

(state for Group C)

### 18 Qualification approval

(state Method 1 or 2 of Clause 4 of IEC Publication 255-10 and, in the first case, refer to Table II, Table IV or Table VI respectively)

#### 19 Quality conformance inspection

- **19.1** With the exception of Sub-group A0, where a sub-group contains more than one test, the order of tests is mandatory.
- 19.2 Samples subjected to destructive tests (D) shall not be released for delivery.

## 20 Marking of relays and packages

Relays and their packages supplied in accordance with this detail specification shall be marked as follows:

#### 20.1 Relay

- trade mark or manufacturer's name
- relay type code
- coded date of manufacture, at least to the nearest month, in accordance with ISO Standard 2015 if appropriate
- (any further necessary marking)

#### 20.2 Packages

- detail specification reference
- trade mark or manufacturer's name
- relay type code
- manufacturer batch identification code
- quantity
- (any further necessary marking)

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## 21 Test schedules

 ${\bf Table\ I-Test\ schedule\ 1\ Quality\ conformance\ inspection\ requirements}$ 

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
	Quality conformance insp Requirements	pection			
	Standard conditions for t Applicable to all tests un				
	77	From Sub-clause 16.7 of IEC Publication 255-7 stat + 1) Atmospheric conditions + 2) Properties of supply and connections + 3) Cleaning and/or adjustment before test 4) Fixing instructions + 5) Application of these conditions	е		1) See IEC Publication 68-1 2) See IEC Publication 443
	Group A inspection	General case	Spec	cial case	}
	Sub-group A0	100 %-test	IL:		II
	For all tests in this sub-g	roup	AQI	L: 0.065	0.25 0.65
1	Visual inspection, marking	M 17.4 1) and 2)			Present and legible
2	Functional tests	M State from 24.3: 1) operate and release value, preconditioning, polarity 5) test on new relays + 6) magnetic orientation × 7) details of monitoring			Correct functioning
3	Dielectric test	M State from 20.2: 1) terminals 2) voltage parameters 3) duration			No breakdown, no flashover + maximum leakage current
4	Sealing	M State from 31.2.2: 1) method 3) pressurizing and cleaning × 4) details of Method 3			Method 1: no visible leakage Methods 2 and 3: maximum leakage rate
	Sub-group A1	IL: I	•		
	For all tests in this sub-g	roup AQL: 0.4 1.0	. 4		
5	D.C. coil resistance	M State from 19.1.3: + 2) reference temperature × 3) temperature coefficient × 4) precautions	Ι		Resistance limit(s) of the coil(s)
6	Coil impedance	M State from 19.3.3: 1) method 3) energization value(s) + 4) test voltage + 5) alternative procedure	Ι		Impedance or burden limits
7	Functional tests	M State from 24.3: Test No. ②	Ι		Correct functioning
	Sub-group A2	IL: S 4	•	•	
	For all tests in this sub-g	roup AQL: 0.4 1.0	. 4		
8	Check of dimensions	R State from 17.7: 1) dimensions + 2) creepage distances and clearances	S 4		Tolerances

 ${\bf Table\ I-Test\ schedule\ 1\ Quality\ conformance\ inspection\ requirements}$ 

Sub-group A3   II.: II   AQL: 0.4 1.0 4	nish and nip to be y s of results  l ents apply
Visual inspection other than marking	nish and nip to be y s of results  l ents apply
than marking	nish and nip to be y s of results  l ents apply
Sub-group B2   IL: S 3   AQL: 0.4 1.0 4	ents apply
For all tests in this sub-group  R State from 32.4: 1) energization value 2) temperature  Solderability Test I (D)  M State from 36.4: 1) method + 2) ageing procedure  Final measurements  State the appropriate conditions and performance requirements applicable to the from the following:  State from 17.7: + 3) visual conditions properties to be checked a) marking and identification b) correct housing  × c) solder wetting  — other final measurements  State all conditions Test No. ⑤  — other final measurements  Group C  IL and AQL are given here only as a guide. Instead of IL and AQL values, the detail specification shall indication shall indicate shall be shall sh	ents apply
Internal moisture  R State from 32.4: 1) energization value 2) temperature  Solderability Test I (D)  M State from 36.4: 1) method + 2) ageing procedure  Final measurements  State the appropriate conditions and performance requirements applicable to the from the following:  State from 17.7: + 3) visual conditions properties to be checked a) marking and identification b) correct housing × c) solder wetting  — d.c. coil resistance  State from 19.1.3: Test No. ⑤  + State all conditions  Group C  IL and AQL are given here only as a guide. Instead of IL and AQL values, the detail specification shall indication    None, but final measurements   S	ents apply
1) energization value 2) temperature    11	ents apply
1) method	
from the following:  State from 17.7: + 3) visual conditions properties to be checked a) marking and identification b) correct housing × c) solder wetting  - d.c. coil resistance  State from 19.1.3: Test No. ⑤ + State all conditions  Group C  IL and AQL are given here only as a guide. Instead of IL and AQL values, the detail specification shall indication.	ents apply
+ 3) visual conditions properties to be checked a) marking and identification b) correct housing × c) solder wetting  - d.c. coil resistance  State from 19.1.3: Test No. ⑤  - other final measurements  - State all conditions  State required  Group C  IL and AQL are given here only as a guide. Instead of IL and AQL values, the detail specification shall indicates    Age of the test above   b) condition to c) wetting independent in the coil (s)	tests above,
Test No. (5) the coil(s)  - other final measurements + State all conditions State required  Group C  IL and AQL are given here only as a guide. Instead of IL and AQL values, the detail specification shall indicate the coil(s) of the coil(s) state required to the coil(s) of th	be satisfactory
measurements  Group C  IL and AQL are given here only as a guide. Instead of IL and AQL values, the detail specification shall indicate the control of the c	it(s) of
IL and AQL are given here only as a guide. Instead of IL and AQL values, the detail specification shall indicate	results
<ol> <li>Periodicity of tests</li> <li>Number of relays to be tested</li> <li>Number of defectives allowed</li> </ol>	ite for each
Sub-group C2 IL: S 3	
For all tests in this sub-group AQL: $0.4 \dots 1.0 \dots 4$	
Dielectric test  M State from 20.2: Test No. ③ Terminals not tested in A0  No breakdown + Maximum le	
Sub-group C3 IL: S 2	eakage current
For all tests in this sub-group AQL: $0.65 \dots 1.5 \dots 6.5$	
Check of dimensions R State from 17.7: 1) dimensions (only from those not yet checked in A2) + 2) creepage-distances and clearances	акаде current
Symbols and circled numbers, see Clauses 12 and 13. <sup>a</sup> Except that due to the normal structure	eakage current

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 ${\bf Table\ I-Test\ schedule\ 1\ Quality\ conformance\ inspection\ requirements}$ 

		Conditions of test			<u>-</u> 
Test	Examination or test	Refer to clause or	IL	AQL	Performance
No.		sub-clause of IEC Publication 255-7		-	requirements
	Sub-group C4	IL: S 2			The tests of this sub-group
	For all tests in this sub-gro	oup AQL: 0.4 1.5 6	3.5		are destructive (D)
15	Electrical endurance (D)	R State from 41.3, 41.4, 41.5, 41.6 as applicable:	S 2		
		For 41.3 (Categories I, II, III)			Method 1:
		State from <b>41.3.2</b> :			allowed number of
		contact(s) to be tested			failures, criteria of failure
		1) number of operations or duration			Method 2: criteria of failure
		2) Method 1 or 2 + 4) checking intervals for Method 2			oritoria or lariare
		+ 6) temperature			
		7) energization value 8) speed and duty factor			
		, ,			
		+ 9) protective devices + 10) checking equipment and fuse rating			
		11) load(s)			
		For 41.4 (Category 0) State from 41.4.2:			Allowed number of failures, the criteria being:
		contact(s) to be tested			the criteria being.
		2) energization value			
		3) speed and duty factor			
		4) number of operations or duration			
		5) contact circuit resistance,			Maximum contact circuit resistance
		state from <b>23.2</b> : (see Test No. (16))			resistance
		+ 6) temperature			
		+ 7) intermediate measurements; state all conditions			Intermediate measurements: state required results
		For 41.5 (Category 0, miss-free)			Maximum contact circuit
		State from 41.5.2: contact(s) to be tested			resistance
		1) energization value			
		2) number of operations 3) speed and duty factor			
		4) contact circuit resistance, state from 23.2:			
		(Test No. (16))			T 4 1: 4
		+ 5) intermediate measurements; state all conditions			Intermediate measurements: state required results
		For <b>41.6</b> (extended assessment) state all information required in IEC 255-0-20. Sub-clause <b>5.2.1.2</b>			State required results
	Final measurements	State the appropriate conditions and performance rec from the following:	quire	ments a	pplicable to the tests above,
16	— insulation resistance	State from 22.2:		e AQL	Minimum value(s) of
		1) terminals + 2) measurement voltage		r the above	insulation resistance
		+ 2) measurement voltage + 3) time to reading	2030		
	— contact circuit	State from 23.2:			Maximum contact circuit
	resistance	+ 1) frequency of test voltage			resistance
		2) type of measurement			
		× 3) details of dynamic test + 4) energization value			
		5) points of measurement			
		6) test current			
		7) open circuit voltage			
	— other final measurements	+ State all conditions			State required results
Symbo	ols and circled numbers, see	Clauses 12 and 13.	•		•

 ${\bf Table\ I-Test\ schedule\ 1\ Quality\ conformance\ inspection\ requirements}$ 

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
	Sub-group C5	IL: S 2	1	1	l
	For all tests in this sub-gr	oup AQL: 0.4 1.0	4		
	This sub-group contains de	estructive tests as marked by a (D)			
.7	Damp heat, steady state (D)	R 27 and 22, state from 27.3: 1) duration, recovery + 2) voltage and for immediate final measurement, state from 22.2: Test No. (16)	S 2		None, but final measurements apply Minimum value(s) of insulation resistance
18	Climatic sequence (D)	R 27 and 22, state if 26.3, 26.5 and/or 26.6 are to be applied  (Dry heat) State from 26.9: 1) severity, recovery 2) energization value, duty and contact load 3) see also 24.3 1) operate and release value + 7) details of monitoring  (Damp heat) State from 26.9: 1) severity, recovery and, for immediate final measurements after the last cycle of 26.6 state from 22.2: Test No. (17)  (Cold) State from 26.9: 1) severity, recovery 5) method 6) operating test requirements, as follows:  Categories I, II and III refer to and state from 41.3.2: contact(s) to be tested 7) energization value 8) speed and duty factor + 9) protective devices + 10) checking equipment 11) load  Category 0 refer to, and state from 41.5.2: contact(s) to be tested 1) energization value 3) speed and duty factor	S 2		Additionally, final measurements apply Correct functioning  None, but final measurements apply Minimum value(s) of insulation resistance  Additionally, final measurements apply  Allowed number of failures, criteria of failure
		and from 23.2: + 1) frequency of test voltage 3) details of dynamic test 5) points of measurement 6) test current 7) open-circuit voltage (Low pressure)			Additionally, final
		State from 26.9: 1) severity, recovery 8) test voltage, duration of voltage test			measurements apply No breakdown, no flashover
		+ Intermediate measurements: State all conditions and the part(s) of the climatic sequence to which they apply			Intermediate measurements state required results

 ${\bf Table\ I-Test\ schedule\ 1\ Quality\ conformance\ inspection\ requirements}$ 

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
19	Robustness of terminals (D) for pull, bend and twist	M State from 35.3: 1) procedure(s) and load(s)	S 2		None, but final measurements apply
20	Shock (D)	R State from 37.3: 1) method 2) pulse shape and acceleration 3) mounting 4) monitoring details 5) energization value(s) × Method 1-test and/or rated × contact load	S 2		Method 1: + opening and closing times Both methods: final measurements apply
21	Bump (D)	R State from 38.4: 1) method 2) acceleration and number 3) mounting + 4) monitoring details 5) energization value(s) × Method 1-test and/or rated × contact load	S 2		Method 1: + opening and closing times Both methods: final measurements apply
22	Vibration (D)	R State from 39.3: 1) vibration parameters 2) energization values, test and rated 3) mounting 4) monitoring details 5) contact load	S 2		+ opening and closing times Additionally, final measurements apply
23	Acceleration (D)	R State from 40.3: 1) method 2) acceleration + duration 3) mounting 4) monitoring details 5) energization value(s) × method I-test and/or rated × contact load	S 2		Method 1: + opening and closing times Both methods: final measurements apply
	Final measurements	State the appropriate conditions and performance rabove, from the following:	require	ments s	till applicable to the tests
24	— visual inspection, general	State from 17.7: + 3) visual conditions properties to be checked a) marking and identification b) correct housing + 4) shaking of the relay + 5) physical properties	as fo	e AQL or the above	a) present and legible b) condition to be satisfactory 4) no audible noise <sup>a</sup> 5) state details of results: × no mechanical deterioration
	— visual inspection, corrosion	+ State particular conditions unless self-evident			No evidence of corrosion which might impair operation
	— d.c. coil resistance	State from 19.1.3: Test No. ⑤			Resistance limit(s) of the coil(s)
	— insulation resistance	State from 22.2: Test No. (16)			Minimum value(s) of insulation resistance
	İ	State from 23.2:			Maximum contact circuit
	<ul><li>— contact circuit resistance</li></ul>	Test No. (16)			resistance

 ${\bf Table~II-Test~schedule~1~Qualification~approval~procedure~requirements}$ 

	_			
	Conditions and r	Conditions and requirements of test		
Examination or test	Refer to clause or sub-clause of IEC Publication 255-7	Description in Table I	Sample size	Allowed defectives
Qualification approval procedure Requirements	•	'	For symbol	s see Clause 12
Standard conditions for testing				
Applicable to all tests unless otherwise spe	cified			
	16	Page 23		
All samples Minimum sample size 18 specimens	1			
Visual inspection, excluding dimensions Dielectric test Functional test	17 20 24	M Sub-group A0/A3 M Sub-group A0 M Sub-group A0		
Sealing	31.2	M Sub-group A0		
Sample group 1 Minimum sample size 5 + 1 specimens	1		ı	I
Coil impedance Robustness of terminals	19.3 35	M Sub-group A1 M Sub-group C5		
Shock Bump Vibration	37 38 39	R Sub-group C5 R Sub-group C5 R Sub-group C5		
Acceleration	40	R Sub-group C5		
Final measurements as applicable  — insulation resistance  — contact-circuit resistance  — other final measurements	22 23 Conditions as for Sub-group C4	× Sub-group C4 × Sub-group C4 + Results as for Sub-group C4	Same criteria as for the test above	
Sample group 2 Minimum sample size 5 + 1 specimens	•			
Solderability, Test 1 Damp heat Climatic sequence	36.3 27 and 22 26 and 22	M Sub-group B2 R Sub-group C5 R Sub-group C5		
Final measurements as applicable  — insulation resistance  — contact-circuit resistance  — other final measurements	22 23 Conditions as for Sub-group C4	× Sub-group C4 × Sub-group C4 + Results as for Sub-group C4	Same criteria above	as for the test
Sample group 3 Minimum sample size 5 + 1 specimens				
Check of dimensions Electrical endurance	17.1 41	M Sub-group A2/C3 M Sub-group C4		
Final measurements as applicable  — insulation resistance  — contact-circuit resistance  — other final measurements	22 23 Conditions as for Sub-group C4	× Sub-group C4 × Sub-group C4 + Results as for Sub-group C4	Same criteria above	as for the test
Symbols and circled numbers, see Clauses	12 and 13.	•	•	

Table III — Test schedule 2 Quality conformance inspection requirements

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements				
	Quality conformance inspecting Requirements	ction	ı	•					
	Standard conditions for testing								
1	Applicable to all tests unless otherwise specified								
		From Sub-clause 16.7 of IEC Publication 255-7 state + 1) Atmospheric conditions + 2) Properties of supply and connections + 3) Cleaning and/or adjustment before test 4) Fixing instructions + 5) Application of these conditions			1) See IEC Publication 68-1 2) See IEC Publication 443				
	Group A inspection	General case	Spec	cial case					
	Sub-group A0	100 %-test	IL:		II				
	For all tests in this sub-gro		AQI	÷ 0.065	0.25 0.65				
1	Visual inspection,	M 17.4 1) and 2)		1	Present and legible				
1	marking	14 17.4 1) and 2)			Tresent and regione				
2	Contact-circuit resistance	<ul> <li></li></ul>			Maximum contact-circuit resistance				
3	Functional test	<ul> <li></li></ul>			Correct functioning				
4	Dielectric test	M State from 20.2: 1) terminals 2) voltage parameters 3) duration			No breakdown, no flashover + maximum leakage current				
5	Sealing	M State from 31.2.2: 1) method 3) pressurizing and cleaning × 4) details of Method 3			Method 1: no visible leakage Methods 2 and 3: maximum leakage rate				
	Sub-group A1	IL: I	1	1					
	For all tests in this sub-gro	AQL: 0.4 1.0 4	4						
6	Internal moisture	R State from 32.4: 1) energization value 2) temperature	Ι		None, but subsequent test to be performed as final measurement				
7	Contact-circuit resistance	№ 23.2 Test No. ②	Ι		Maximum contact circuit resistance				
8	D.C. coil resistance	<ul> <li>M State from 19.1.3:</li> <li>+ 2) reference temperature</li> <li>× 3) temperature coefficient</li> <li>× 4) precautions</li> </ul>	Ι		Resistance limit(s) of the coil(s)				
9	Coil impedance	M State from 19.3: 1) method 3) energization value(s) + 4) test voltage + 5) alternative procedure	Ι		Impedance or burden limits				
10	Mechanical tests	R State from 18.3: 1) properties to be tested, methods of test	Ι		State required results				
		M 24.3 Test No. (3)			Correct functioning				

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Table III — Test schedule 2 Quality conformance inspection requirements

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
	Sub-group A2	IL: S 4			l
	For all tests in this sub-gre	oup AQL: 0.4 1.0	. 4		
12	Check of dimensions	M State from 17.7: 1) dimensions + 2) creepage distances and clearances	S 4		Tolerances
	Sub-group A3	IL: II	I		
	For all tests in this sub-gr	oup AQL: 0.4 1.0	. 4		
13	Visual inspection, other than marking	M State from 17.7: + 3) visual conditions + 4) shaking of the relay a) 5) correct housing b) + other physical properties c)	II		a) no audible noise <sup>a</sup> b) condition, finish and workmanship to be satisfactory c) state details of results
	Sub-group $A4$	IL: S 4			
	For all tests in this sub-gre	oup AQL: 0.4 1.0	. 4		
14	Dielectric test	M <b>20.2</b> Test No. <b>(4)</b>	S 4		No breakdown, no flashover + maximum leakage curren
	Group B  Sub-group B1  For all tests in this sub-group B1	ı	. 6.5		The test of this sub-group is destructive (D
.5	Electrical endurance (D)	R State from 41.3, 41.4, 41.5 or 41.6 as applicable	S 3		
		For 41.3 (Categories I, II, III) State from 41.3.2: contact(s) to be tested 1) number of operations or duration 2) Method 1 or 2 + 4) checking intervals for Method 2 + 6) temperature 7) energization value 8) speed and duty factor + 9) protective devices + 10) checking equipment and fuse rating			Method 1:     allowed number of     failures, criteria of failure Method 2:     criteria of failure
		11) load(s) 12) final measurements Test No. 27 Test No. 2 + other measurements, state all conditions			Final measurements: minimum values of insulation resistance, maximum contact resistance, state require results
		For 41.4 (Category 0) State from 41.4.2: contact(s) to be tested 2) energization value 3) speed and duty factor 4) number of operations or duration			Allowed number of failures the criterion being:
		5) contact-circuit resistance, state from 23.2: (see Test No. (2)) + 6) temperature			Maximum contact-circuit resistance
		+ 7) intermediate measurements state all condition	s		Intermediate measurement state required results
		8) final measurements Test No. 27 + other final measurements, state all conditions			Final measurements: minimum values of insulation resistance, state required results

Table III — Test schedule 2 Quality conformance inspection requirements

		est schedule 2 Quality conformance ins	peci	1011 1	equirements
Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
15	Electrical endurance (D)	For 41.5 (Category 0, miss-free)	S 3		
		State from 41.5.2: contact(s) to be tested 1) energization value 2) number of operations 3) speed and duty factor 4) contact-circuit resistance, state from 23.2: (Test No. ②) + 5) intermediate measurements, state all conditions			Maximum contact-circuit resistance Intermediate measurements: state required results
		6) final measurements Test No. 27 + other final measurements, state all conditions			Final measurements: minimum values of insulation resistance state required results
		For 41.6 (extended assessment) state all information required by IEC Publication 255-0-20, Sub-clause 5.2.1.2			State all required results
	Sub-group B2	IL: S 3		I.	1
	For all tests in this sub-gre	oup AQL: 0.4 1.0 4	1		
	This sub-group contains de	estructive tests as marked by a (D)			
16	Magnetic remanence	R 54 and 25, state from 54.3: 1) saturate values,	S 3		Limits of remanence value + duration of discontinuities
		+ duration of application 2) contact criteria and from 25.3: 1) mounting or position 5) contact parameters 8) contact to be checked × 10) suppression components			to be ignored
17	Temperature rise	R State from 29.3: 1) mounting 2) energization value, × duration × 3) conductor material + 4) temperature + 5) contact load	S 3		Limits of temperature rise
18	Rapid change of	M State from 30.3:	S 3		None, but final
	temperature, Method 2	2) temperature parameters + 3) contact load			measurements apply
19	Solderability Test 1 (D)	M State from 36.4: 1) method + 2) ageing procedure	S 3		None, but final measurements apply
20	Robustness of terminals (D) for pull, bend and twist	M State from 35.3: 1) procedure(s) and load(s)	S 3		None, but final measurements apply
	Final measurements	State the appropriate conditions and performance red from the following:	quirer	nents a	
21	— visual inspection	State from 17.7: + 3) visual conditions properties to be checked a) marking and identification b) correct housing × c) corrosion × d) solder wetting	as fo	e AQL or the above	a) present and legible b) condition to be satisfactory c) corrosion index d) wetting index
	— insulation resistance	22.2 Test No. (27)			Minimum value(s) of insulation resistance
	— d.c. coil resistance	19.1.3 Test No. (8)			Resistance limit(s) of the coil(s)
Symb	ols and circled numbers, see	e Clauses 12 and 13.			

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Table III — Test schedule 2 Quality conformance inspection requirements

No.	Examination or test	Conditions of t Refer to clause sub-clause of IEC Publi	or	IL	AQL	Performance requirements
	— contact circuit resistance	23.2 Test No. (2)				Maximum contact-circuit resistance
	— other final measurements	+ State all conditions				State required result
	Sub-group B3		IL: S 3			
	For all tests in this sub-gr	oup	AQL: 0.1 $\theta$ .65	2.5		
22	Contact sticking	M 53 and 25, state from 53.3: upper temperature 1) upper limit of operative rar and from 25.3:	age	S 3		Limit of release time + duration of discontinuities to be ignored
		1) mounting or position     + 3) means of disconnection     5) contact parameters     8) contact(s) to be checked     × 10) suppression components				
	Group C					
	sub-group:  1) Periodicity of tests  2) Number of relays to be  3) Number of defectives al			tail s	pecifica	
	Sub-group C1		IL: S 2			The test of this
	For all tests in this sub-gr		AQL: 0.4 1.5 6			sub-group is destructive
23	Electrical endurance	R 41 Test No. (15)		S 2		Test No. 15
	Sub-group C2		IL: S 3			
	For all tests in this sub-gr	oup	AQL: 0.4 1.0 4	Į.		
24				S 3	•••	Maximum contact-circuit resistance
25	Timing test	M State from 25.3:  1) mounting or position 2) energization parameters + 3) means for disconnection 4) supply parameters 5) contact parameters		S 3		Limits of times to be measured + duration of discontinuities to be ignored
		× 7) further details 8) contact(s) to be checked × 10) suppression components				
26	Dielectric test	8) contact(s) to be checked		S 3		No breakdown, no flashover + maximum leakage current
	Dielectric test  Insulation resistance	8) contact(s) to be checked × 10) suppression components		S 3		
	Insulation resistance	8) contact(s) to be checked × 10) suppression components  M 20.2 Test No. (4)  R State from 22.2: 1) terminals + 2) measurement voltage	II.: S 2			+ maximum leakage current Minimum value(s) of insulation resistance
		8) contact(s) to be checked × 10) suppression components  1 20.2 Test No. (4)  R State from 22.2: 1) terminals + 2) measurement voltage + 3) time to reading	IL: S 2 AQL: 0.65 1.5	S 3		+ maximum leakage current Minimum value(s) of
27	Insulation resistance Sub-group C4	8) contact(s) to be checked × 10) suppression components  1 20.2 Test No. (4)  R State from 22.2: 1) terminals + 2) measurement voltage + 3) time to reading		S 3		+ maximum leakage current Minimum value(s) of insulation resistance  The test of this
26 27 28 29	Insulation resistance $Sub\text{-}group \ C4$ For all tests in this sub-gr	8) contact(s) to be checked × 10) suppression components  M 20.2 Test No. (4)  R State from 22.2: 1) terminals + 2) measurement voltage + 3) time to reading	AQL: 0.65 1.5	S 3		+ maximum leakage current Minimum value(s) of insulation resistance  The test of this sub-group is destructive

 ${\bf Table~III-Test~schedule~2~Quality~conformance~inspection~requirements}$ 

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
	Final measurements	State the appropriate conditions and performance re from the following:	quire	ments a	pplicable to the tests above,
30	— visual inspection	State from 17.7: + 3) visual conditions properties to be checked a) marking and identification b) correct housing + 4) shaking of the relay + 5) other physical properties	as fo	e AQL or the above	a) present and legible     b) condition to be satisfactory     4) no audible noise <sup>a</sup> 5) state details of result
	— insulation resistance	<b>22.2</b> Test No. <b>27</b>			Minimum value(s) of insulation resistance
	— contact circuit resistance	<b>3.2</b> Test No. (2)			Maximum contact circuit resistance
ĺ	— other final measurements	+ State all conditions			State required results
	Sub-group C5	IL: S 2	•		L
1	For all tests in this sub-gr	roup AQL: 0.4 1.0	4		
	This sub-group contains d	estructive tests as marked by a (D)			
31	Damp heat, steady state (D)	R 27 and 22, state from 27.3: 1) duration, recovery + 2) voltage and, for immediate final measurements, state from 22.2: Test No. 27	S 2		None, but final measurements apply Minimum value(s) of insulation resistance
	ols and circled numbers, se	R 26 and 22. State if 26.3, 26.5 and/or 26.6 are to be applied  (Dry heat) State from 26.9: 1) severity, recovery 2) energization value, duty and contact load 3) see also 24.3 1) operate and release value + 7) details of monitoring  (Damp heat) State from 26.9: 1) severity, recovery and, for immediate final measurement after the last cycle of 26.6, state from 22.2: Test No. 27  (Cold) State from 26.9: 1) severity, recovery 5) method 6) operating test requirements, as follows:	S 2		Additionally, final measurements apply  Correct functioning  None, but final measurements apply Minimum value(s) of insulation resistance  Additionally, final measurements apply

<sup>a</sup> Except that due to the normal structure

 ${\bf Table~III-Test~schedule~2~Quality~conformance~inspection~requirements}$ 

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
32	climatic sequence (D)	Categories I, II and III refer to and state from 41.3.2: contact(s) to be tested 7) energization value 8) speed and duty factor + 9) protective devices	S 2		Allowed number of failures, criteria of failure
		+ 10) checking equipment 11) load Category 0 refer to, and state from 41.5.2: contact(s) to be tested 1) energization value 3) speed and duty factor			Maximum contact circuit resistance
		and from 23.2: + 1) frequency of test voltage 3) details of dynamic test 5) points of measurement 6) test current 7) open-circuit voltage			
		(Low pressure) State from 26.9: 1) severity, recovery 8) test voltage duration of dielectric test			Additionally, final measurements apply No breakdown, no flashover
		+ Intermediate measurements: State all conditions and the part(s) of the climatic sequence to which they apply			Intermediate measurements State required result
33	Salt mist (D)	R State from 33.1.4: 1) duration 2) recovery	S 2		None, but final measurements apply
34	Robustness of terminals (D) for pull, bend and twist	№ 35.3 Test No. (20)	S 2		None, but final measurements apply
35	Shock (D)	R State from 37.4:  1) method 2) pulse shape and acceleration 3) mounting 4) monitoring details 5) energization value(s)  × Method 1-test and/or rated × contact load	S 2		Method 1: + opening and closing times Both methods: final measurements apply
36	Bump (D)	R State from 38.4:  1) method 2) acceleration and number 3) mounting + 4) monitoring details 5) energization value(s) × Method 1-test and/or rated × contact load	S 2		Method 1: + opening and closing times Both methods: final measurements
37	Vibration (D)	R State from 39.3: 1) vibration parameters 2) energization values, test and rated 3) mounting 4) monitoring details 5) contact load	S 2		+ opening and closing times Additionally, final measurements apply

Table III — Test schedule 2 Quality conformance inspection requirements

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
38	Acceleration (D)	R State from 40.4: 1) method 2) acceleration + duration 3) mounting 4) monitoring details 5) energization value(s) × Method 1-test and/or rated × contact load	S 2		Method 1: + opening and closing times Both methods: final measurements apply
	Final measurements	State the appropriate conditions and performance reabove, from the following:	equire	ments s	till applicable to the tests
39	— visual inspection, general	State from 17.7:  + 3) visual conditions properties to be checked a) marking and identification b) correct housing + 4) shaking of the relay + 5) physical properties × surface	as fo	e AQL or the above	<ul> <li>a) present and legible</li> <li>b) condition to be satisfactory</li> <li>4) no audible noise<sup>a</sup></li> <li>5) state details of results</li> <li>× no mechanical deterioration</li> <li>× no peeling or chipping</li> </ul>
	— visual inspection, corrosion	+ State particular conditions unless self-evident			No evidence of corrosion which might impair operation
	— d.c. coil resistance	19.1.3 Test No. (8)			Resistance limit(s) of the coil(s)
	— insulation resistance	22.2 Test No. (27)			Minimum value(s) of insulation resistance
	— contact circuit resistance	23.2 Test No. (2)			Maximum contact circuit resistance
	— other final measurements	+ State all conditions			State required results
	Sub-group C5 For all tests in this sub-gr This sub-group contains d	IL: S 2 roup AQL: $1.5 \dots 2.5 \dots$ estructive tests as marked by a (D)	6.5		
40	Thermal resistance	R State from 28.3: 1) mounting 2) energization values of operative range × 3) temperature coefficient + 4) evaluation procedure + 6) contact load	S 2		Limits of thermal resistance
41	Rapid change of temperature (D)	R State from 30.3: 1) method 2) temperature, duration + 3) contact load	S 2		None, but final measurements apply
42	Soldering: Test 2 (D)	R State from 36.4: 1) method	S 2		None, but final measurements apply

 ${\bf Table~IV-Test~schedule~2~Qualification~approval~procedure~requirements}$ 

	Conditions and	requirements of test			
Examination or test	Refer to clause or sub-clause of IEC Publication 255-7	Description in Table I	Sample size	Allowed defectives	
Qualification approval procedure		For	symbols see	Clause 12	
Requirements					
Standard conditions for testing					
Applicable to all tests unless otherwise sp	pecified				
	16	Page 23			
All samples			ı		
Minimum sample size 24 specimens					
Visual inspection, excluding dimensions	17	M Sub-group A0/A3			
Dielectric test	20	M Sub-group A0/A3 M Sub-group A0	•••	•••	
Contact-circuit resistance	23	M Sub-group A0		•••	
D.C. coil resistance	19.1	M Sub-group A0 M Sub-group A1	•••	•••	
D.C. con resistance	10.1	M Sub-group A1	•••	•••	
Functional test	24	M Sub-group A1			
Sealing	31.2	M Sub-group A0			
	01.2	η ε αυ group πο	1	I	
Sample group 1					
Minimum sample size 5 + 1 specimens		T	_	1	
Internal moisture	32	M Sub-group A1	•••		
Coil impedance	19.3	M Sub-group A1	•••		
Magnetic remanence	<b>54</b> and <b>25</b>	R Sub-group B2	•••	•••	
Contact sticking	<b>53</b> and <b>25</b>	R Sub-group B3	•••	•••	
Mechanical tests	18.1	R Sub-group A1	•••	•••	
Insulation resistance	22	M Sub-group C3	•••	•••	
Thermoelectric e.m.f.	51	R Sub-group C5	•••	•••	
Robustness of terminals	35	M Sub-group C5	•••	•••	
Shock	37	R Sub-group C5			
Bump	38	R Sub-group C5			
Vibration	39	R Sub-group C5	•••	•••	
Acceleration	40	R Sub-group C5	•••	•••	
Final measurements, as applicable					
— visual inspection	17	× Sub-group C5			
— d.c. coil resistance	19.1	× Sub-group C5			
			Same criter		
— insulation resistance	22	× Sub-group C5	the test a	above	
— contact-circuit resistance	23	× Sub-group C5			
— other final measurements	Conditions as for	+ results as for			
	Sub-group C5	Sub-group C5			
Symbols and circled numbers, see Clause	s <b>12</b> and <b>13</b> .	•	•		

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 ${\bf Table~IV-Test~schedule~2~Qualification~approval~procedure~requirements}$ 

	Conditions and	requirements of test		
Examination or test	Refer to clause or sub-clause of IEC Publication 255-7	Description in Table I	Sample size	Allowed defectives
Sample group 2				
Minimum sample size 5 + 1 specimens				
Solderability, Test 1	36.3	M Sub-group B2	•••	
Rapid change of temperature, Method 1	30	M Sub-group B2		
Damp heat	<b>27</b> and <b>22</b>	R Sub-group C5		
Climatic sequence	<b>26</b> and <b>22</b>	R Sub-group C5		•••
Salt mist	33.1	R Sub-group C5		•••
Final measurements, if still applicable				l .
— visual inspection	17	× Sub-group C5		
— d.c. coil resistance	19.1	× Sub-group C5		
		John group of	Same criter	ria as for
— insulation resistance	22	× Sub-group C5	the test a	above
— contact-circuit resistance	23	× Sub-group C5		
— other final measurements	Conditions as for	+ results as for		
	Sub-group C5	Sub-group C5		
Sample group 3			•	
Minimum sample size 5 + 1 specimens				
Check of dimensions	17.1	M Sub-group A2		
Weighing	18.2	R Sub-group C3		
Electrical endurance	41	M Sub-group C4		•••
Mechanical endurance	42	M Sub-group C4		
Final measurements, as applicable				l .
— visual inspection	17	× Sub-group C4		
— insulation resistance	22	× Sub-group C4	Same criter	ria as for
— contact-circuit resistance	23	× Sub-group C4	the test a	above
— other final measurements	Conditions as for	+ results as for		
	Sub-group C4	Sub-group C4		
Sample group 4		<u> </u>		
Minimum sample size 5 + 1 specimens				
Thermal resistance	28	R Sub-group C6		
Temperature rise	29	R Sub-group B2		•••
Rapid change of temperature,	30	R Sub-group C6		•••
Method 2				
Solderability, Test 2	36.3	R Sub-group C6		
Final measurements, as applicable				•
— visual inspection	17	× Sub-group C6		
— d.c. coil resistance	19.1	× Sub-group C6		
			Same criter	
— insulation resistance	22	× Sub-group C6	the test a	above
— contact-circuit resistance	23	× Sub-group C6		
— other final measurements	Conditions as for	+ results as for		
	Sub-group C6	Sub-group C6		
Symbols and circled numbers, see Clause	es <b>12</b> and <b>13</b> .			

Table V — Test schedule 3 Quality conformance inspection requirements

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
	Quality conformance inspecting Requirements	ction	<u> </u>		
	Standard conditions for tes				
	Applicable to all tests unle	<del>-</del>		1	T
		From Sub-clause 16.7 of IEC Publication 255-7 sta + 1) atmospheric conditions + 2) properties of supply and connections + 3) cleaning and/or adjustment before test 4) fixing instructions + 5) application of these conditions	ate		1) See IEC Publication 68-1 2) See IEC Publication 443
	Group A inspection	General case	Spec	ial case	<u> </u>
	Sub-group A0	100 %-test	IL:		II
	For all tests in this sub-gro			: 0.065	0.25 0.65
1	Visual inspection,	M 17.4. 1) and 2)			Present and legible
	marking	W State from 23.2:			25
2	Contact-circuit resistance	1) State from 23.2:  + 1) frequency of test voltage 2) type of measurement  × 3) details of dynamic test  + 4) energization value 5) points of measurement 6) test current 7) open circuit voltage			Maximum contact-circuit resistance
3	D.C. coil resistance	M State from 19.1:			Resistance limit(s) of
0	D.C. con resistance	+ 2) reference temperature × 3) temperature coefficient × 4) precautions			the coil(s)
4	Functional tests	<ul> <li></li></ul>			Correct functioning
5	Dielectric test	M State from 20.2: 1) terminals 2) voltage parameters 3) duration			No breakdown, no flashove + maximum leakage currer
6	Sealing	↑ State from 31.2.2:     1) method     3) pressurizing and cleaning     × 4) details of Method 3			Method 1: no visible leakage Methods 2 and 3: maximum leakage rate
	Sub-group A1	IL: I		ı	l
	For all tests in this sub-gro	oup AQL: 0.4 1.0	4		
7	Internal moisture	R State from <b>32.4</b> : 1) energization value 2) temperature	Ι		None, but subsequent test to be performed as final measurement
8	Contact-circuit resistance	M 23.2 Test No. (2)	I		Maximum contact-circuit resistance
9	D.C. coil resistance	№ 19.1.3 Test No. ③	I		Resistance limit(s) of the coil(s)
0	Coil impedance	M State from 19.3.3: 1) method 3) energization value(s) + 4) test voltage + 5) alternative procedure	Ι		Impedance or burden limit
1	Functional test	M 24 Test No. (4)	Ι		Correct functioning

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Table V — Test schedule 3 Quality conformance inspection requirements

Test No.	Examination or test	Conditions of t Refer to clause sub-clause of IEC Public	or	IL	AQL	Performance requirements
12	Timing tests	R State from 25.3:	sation 200 i	Ι		Limits of the times to be
- <b>-</b>	111111111111111111111111111111111111111	1) mounting or position		_		measured
		2) energization parameters				+ duration of discontinuities
		+ 3) means for disconnection				tot be ignored
		4) supply parameters				
		5) contact parameters				
		× 7) further details				
		8) contact(s) to be checked				
9	Maskanialtanta	× 10) suppression components R State from 18.3:		т		C+++
.3	Mechanical tests	1) properties to be tested, meth	ada of tost	Ι	•••	State required results
	C 1 . 40	1) properties to be tested, meth				
	Sub-group $A2$					
	For all tests in this sub-gr	•	AQL: 0.4 1.0 4			
.4	Check of dimensions	M State from 17.7:		S 4		Tolerances
		1) dimensions				
		+ 2) creepage distances and clear				
	Sub-group $A3$		IL: II			
	For all tests in this sub-gr	oup	AQL: 0.4 1.04			
15	Visual inspection, other	M State from 17.7:		II		a) no audible noise <sup>a</sup>
	than marking	+ 3) visual conditions				b) condition, finish and
		+ 4) shaking of the relay a)				workmanship to be
		5) correct housing b)				satisfactory
		+ other physical properties c)				c) state details of results
	Sub-group A4		IL: S 4			
	For all tests in this sub-gr	oup	AQL:0.4 $1.0$ $4$			
6	Insulation resistance	M State from 22.2:		S 4		Minimum value(s) of
		1) terminals				insulation resistance
		+ 2) measurement voltage				
		+ 3) time to reading				
7	Dielectric test	M <b>20.2</b> Test No. (5)		S 4		No breakdown, no flashover
						+ maximum leakage current
	Group B					
	Sub-group B1		IL: S 3			The test of this sub-group is
	For all tests in this sub-gr	oup	AQL: 0.4 1.5 6	3.5		destructive
8	Electrical endurance (D)	R State from 41.3, 41.4, 41.5 or 4	1 6 as annlicable	S 3		
0	nicotrical chautanee (b)	(Categories I, II, III)	1.0 as applicable.	20		Method 1:
		State from 41.3.2: contact(s) to	ho tostod			allowed number of
		1) number of operations or du				failures, criteria of failur
		2) Method 1 or 2	auton			Method 2:
		+ 4) checking intervals for Meth	nod 2			criteria of failure
		+ 6) temperature 7) energization value				
		8) speed and duty factor				
		o) speed and duty factor				
		+ 9) protective devices + 10) checking equipment and fu	se rating			
		+ 10) checking equipment and fu	se rating			
		7 =	se rating			Final measurements:
		+ 10) checking equipment and fu 11) load(s)	se rating			minimum values of
		+ 10) checking equipment and fu 11) load(s) 12) final measurements	se rating			minimum values of insulation resistance,
		+ 10) checking equipment and fu 11) load(s) 12) final measurements Test No. (6)				minimum values of insulation resistance, maximum contact-circuit
		+ 10) checking equipment and fu 11) load(s) 12) final measurements Test No. 16 Test No. 2				minimum values of insulation resistance,

	Table V — Te	st schedule 3 Quality conformance insp	ect	ion re	equirements
Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements
18	Electrical endurance (D)	(Category 0) State from 41.4.2: contact(s) to be tested 2) energization value	S 3		Allowed number of failures, the criteria of failure being:
		3) speed and duty factor			Maximum contact-circuit
		4) number of operations or duration 5) contact-circuit resistance. state from 23.2: (see Test No. (2))			resistance
		+ 6) temperature + 7) intermediate measurements; state all conditions			Intermediate measurements: state required results
		8) final measurements Test No. (16) + other final measurements; state all conditions			Final measurements: minimum values of insulation resistance state required results
		(Category 0, miss-free) State from 41.5.2: contact(s) to be tested 1) energization value 2) number of operations 3) speed and duty factor 4) contact-circuit resistance,			Maximum contact-circuit resistance
		state from 23.2: (Test No. ②) + 5) intermediate measurements: state all conditions			Intermediate measurements:
		6) final measurements Test No. (16) + other final measurements: state all conditions			state required results Final measurements: minimum values of insulation resistance. state all required results
		For 41.6 (extended assessment) state all information required in IEC Publication 255-0-20, Sub-clause 5.2.1.2			State all required results
	Sub-group B2	IL: S 3	1	l	
	For all tests in this sub-gre	oup AQL: 0.4 1.0 4	4		
	This sub-group contains de	estructive tests as marked by a (D)			
19	Magnetic remanence	R 54 and 25, state from 54.3: 1) saturate values, + duration of application 2) contact criteria and from 25.3: 1) mounting or position 5) contact parameters 8) contact to be checked	S 3		Limits of remanence value + duration of discontinuities to be ignored
20	Tomonostumo mico	× 10) suppression components R State from 29.3:	S 3		Limits of town one type wise
20	Temperature rise	1) mounting 2) energization value, × duration × 3) conductor material + 4) temperature + 5) contact load	53		Limits of temperature rise
21	Rapid change of temperature, Method 2	M State from 30.3: 2) temperature parameters + 3) contact load	S 3		None, but final measurements apply
22	Solderability, Test 1 (D)	M State from 36.4: 1) method + 2) ageing procedure	S 3		None, but final measurements apply
23	Robustness of terminals (D) for pull, bend and twist	M State from 35.3: 1) procedure(s) and load(s)	S 3		None, but final measurements apply
Symbo	ols and circled numbers, see	Clauses 12 and 13.	•	•	

 ${\bf Table\ V-Test\ schedule\ 3\ Quality\ conformance\ inspection\ requirements}$ 

No.	Examination or test	Conditions of t Refer to clause sub-clause of IEC Public	or	IL	AQL	Performance requirements	
	Final measurements	State the appropriate conditions from the following:	anditions and performance requirements applicable to the tests a				
24	— visual inspection	State from 17: + 3) visual conditions properties to be checked a) marking and identification b) correct housing × c) corrosion × d) solder wetting			e AQL or the above	a) present and legible     b) condition to be satisfactory     c) corrosion index     d) wetting index	
	— insulation resistance	22.2 Test No. (16)				Minimum value(s) of insulation resistance	
	— d.c. coil resistance	19.1.3 Test No. (3)				Resistance limit(s) of the coil(s)	
	— contact-circuit resistance	23.2 Test No. (2)				Maximum contact circuit resistance	
	— other final measurements	+ State all conditions				State required results	
	Sub-group B3		IL: S 3				
	For all tests in this sub-gre	oup	AQL: 0.1 0.65	2.5			
25	Contact sticking	R 53 and 25, state from 53.3: upper temperature 1) upper limit of operative ran and from 25.3: 1) mounting or position + 3) means of disconnection 5) contact parameters 8) contact(s) to be checked × 10) suppression components	ge	S 3		Limit of release time + duration of discontinuities to be ignored	
		e only as a guide. Instead of IL and	l AQL values, the de	tail s	pecifica	tion shall indicate for each	
	=	e only as a guide. Instead of IL and	l AQL values, the de	tail s	pecifica	The test of this sub-group is	
	IL and AQL are given here sub-group: 1) Periodicity of tests 2) Number of relays to be to 3) Number of defectives all	e only as a guide. Instead of IL and sested lowed			pecifica		
26	IL and AQL are given here sub-group: 1) Periodicity of tests 2) Number of relays to be to 3) Number of defectives all Sub-group C1	e only as a guide. Instead of IL and sested lowed	IL: S 2		pecifica	The test of this sub-group is	
26	IL and AQL are given here sub-group: 1) Periodicity of tests 2) Number of relays to be to 3) Number of defectives all Sub-group C1 For all tests in this sub-group	e only as a guide. Instead of IL and tested lowed	IL: S 2	5.5		The test of this sub-group is destructive (D)	
26	IL and AQL are given here sub-group: 1) Periodicity of tests 2) Number of relays to be to 3) Number of defectives all Sub-group C1 For all tests in this sub-group Electrical endurance	e only as a guide. Instead of IL and tested lowed oup	IL: S 2 AQL: 0.4 1.5 6	S 2		The test of this sub-group is destructive (D)	
	IL and AQL are given here sub-group: 1) Periodicity of tests 2) Number of relays to be to 3) Number of defectives all Sub-group C1 For all tests in this sub-group C2  Electrical endurance  Sub-group C2	e only as a guide. Instead of IL and tested lowed   R Test No. (18)	IL: S 2 AQL: 0.4 1.5 6 IL: S 3	S 2		The test of this sub-group is destructive (D)	
27	IL and AQL are given here sub-group: 1) Periodicity of tests 2) Number of relays to be to 3) Number of defectives all Sub-group C1 For all tests in this sub-group C2 For all tests in this sub-group C2 For all tests in this sub-group C2	e only as a guide. Instead of IL and tested lowed   R Test No. (18)	IL: S 2 AQL: 0.4 1.5 6 IL: S 3 AQL: 0.4 1.0 4	S 2		The test of this sub-group is destructive (D)  Test No. (18)  Maximum contact-circuit	
227	IL and AQL are given here sub-group:  1) Periodicity of tests 2) Number of relays to be to 3) Number of defectives all Sub-group C1  For all tests in this sub-group C2  For all tests in this sub-group C2  For all tests in this sub-group C2  Contact-circuit resistance	R State from 19.2.3:  2) measurement voltage  3) measurement frequency 4) energization value	IL: S 2 AQL: 0.4 1.5 6 IL: S 3 AQL: 0.4 1.0 4	S 2 S 3		The test of this sub-group is destructive (D)  Test No. (18)  Maximum contact-circuit resistance  Coil inductance limits, unenergized and	
227 228 229	IL and AQL are given here sub-group:  1) Periodicity of tests 2) Number of relays to be to 3) Number of defectives all Sub-group C1 For all tests in this sub-group C2 For all tests in this sub-group C2 For all tests in this sub-group C2 Contact-circuit resistance Coil inductance	R State from 19.2.3:  2) measurement voltage  3) measurement frequency 4) energization value + 5) details of alternative procedu	IL: S 2 AQL: 0.4 1.5 6 IL: S 3 AQL: 0.4 1.0 4	S 2 S 3 S 3		The test of this sub-group is destructive (D)  Test No. (18)  Maximum contact-circuit resistance  Coil inductance limits, unenergized and energized state  Limits of times to be measured + duration of discontinuities	
227 228 229	IL and AQL are given here sub-group:  1) Periodicity of tests  2) Number of relays to be to 3) Number of defectives all Sub-group C1  For all tests in this sub-group C2  For all tests in this sub-group C2  For all tests in this sub-group C2  Contact-circuit resistance  Coil inductance  Timing tests	e only as a guide. Instead of IL and tested lowed  The state of the st	IL: S 2 AQL: 0.4 1.5 6 IL: S 3 AQL: 0.4 1.0 4	S 3 S 3		The test of this sub-group is destructive (D)  Test No. (18)  Maximum contact-circuit resistance  Coil inductance limits, unenergized and energized state  Limits of times to be measured + duration of discontinuities to be ignored  No breakdown, no flashover	
227 228 229	IL and AQL are given here sub-group:  1) Periodicity of tests  2) Number of relays to be to 3) Number of defectives all Sub-group C1  For all tests in this sub-group C2  For all tests in this sub-group C2  For all tests in this sub-group C2  Contact-circuit resistance  Coil inductance  Dielectric test	e only as a guide. Instead of IL and tested lowed  oup  If Test No. (18)  Oup  M 23.2 Test No. (2)  R State from 19.2.3: 2) measurement voltage 3) measurement frequency 4) energization value + 5) details of alternative procedu M 25.3 Test No. (12)  M 20.2 Test No. (5)	IL: S 2 AQL: 0.4 1.5 6 IL: S 3 AQL: 0.4 1.0 4	S 2 S 3 S 3 S 3		The test of this sub-group is destructive (D)  Test No. (18)  Maximum contact-circuit resistance  Coil inductance limits, unenergized and energized state  Limits of times to be measured + duration of discontinuities to be ignored  No breakdown, no flashover	
226 227 228 229 330	IL and AQL are given here sub-group:  1) Periodicity of tests  2) Number of relays to be to 3) Number of defectives all Sub-group C1  For all tests in this sub-group C2  For all tests in this sub-group C2  For all tests in this sub-group C2  Contact-circuit resistance  Coil inductance  Timing tests  Dielectric test  Sub-group C3	e only as a guide. Instead of IL and tested lowed  oup  If Test No. (18)  Oup  M 23.2 Test No. (2)  R State from 19.2.3: 2) measurement voltage 3) measurement frequency 4) energization value + 5) details of alternative procedu M 25.3 Test No. (12)  M 20.2 Test No. (5)	IL: S 2 AQL: 0.4 1.5 6 IL: S 3 AQL: 0.4 1.0 4	S 2 S 3 S 3 S 3		The test of this sub-group is destructive (D)  Test No. (18)  Maximum contact-circuit resistance  Coil inductance limits, unenergized and energized state  Limits of times to be measured + duration of discontinuities to be ignored  No breakdown, no flashover	

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 ${\bf Table\ V-Test\ schedule\ 3\ Quality\ conformance\ inspection\ requirements}$ 

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements	
32	Contact noise	R State from 50.3: 1) energization value(s) + 2) shock and/or vibration parameters (see C5) 3) test circuit 4) measuring equipment	S 2		Limits of noise voltage	
	Sub-group C4 For all tests in this sub-gr	IL: S 2 roup AQL: 0.65 1.5	. 6.5		The tests of this sub-group are destructive	
33	Electrical endurance	M 41 Test No. (18)	S 2		Test No. (18)	
34	Mechanical endurance (D)	M State from 42.4 taking into account Note 4 of Appendix B of IEC Publication 255-10:  1) Method 1 or 2 2) energization value  × 3) monitoring parameters 4) speed and duty factor 5) number of operations or duration  × 7) intermediate checks, state all details	of S 2		Method 1: allowed number of failures Method 2 state required results	
	Final measurements	State the appropriate conditions and performance re from the following:	quire	nents a	pplicable to the tests above,	
35	— visual inspection	State from 17.7:  + 5) visual conditions Properties to be checked a) marking and identification b) correct housing + 4) shaking of the relay + 5) other physical properties	as fo	e AQL or the above	a) present and legible     b) condition to be satisfactor     4) no audible noise <sup>a</sup> 5) state details of results	
	— insulation resistance	22.2 Test No. (16)			Minimum value(s) of insulation resistance	
	— contact circuit resistance	23.2 Test No. (2)			Maximum contact-circuit resistance	
	— other final measurements	+ State all conditions			State required results	
	Sub-group C5	IL: S 2				
	For all tests in this sub-gr This sub-group contains d	oup AQL: $0.4 \dots 1.0 \dots$ estructive tests as marked by a (D)	4			
36	Thermoelectric e.m.f.	R State from 51.3: 1) method and material for soldering 2) ambient temperature	S 2		Limit of e.m.f.	
37	Thermal endurance (D)	R 43 and 24, state from 43.3: 1) mounting 2) duration 3) ambient temperature 4) energization value contact load and, for immediate final measurements, state from 24.3: 1) operate and release value + 7) details of monitoring	S 2		None, but final measurements apply Correct functioning	
38	Damp heat, steady state (D)	R 27 and 22, state from 27.3: 1) duration, recovery + 2) voltage and, for immediate final measurements, Test No. (16)	S 2		None, but final measurements apply Minimum value(s) of insulation resistance	

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 ${\bf Table\ V-Test\ schedule\ 3\ Quality\ conformance\ inspection\ requirements}$ 

		Conditions of test			
Test No.	Examination or test	Refer to clause or	IL	$\mathbf{AQL}$	Performance requirements
		sub-clause of IEC Publication 255-7			requirements
39	Climatic sequence (D)	R 26 and 22, state if 26.3, 26.5 and/or 26.6 are to be applied	S 2		
		(Dry heat)			Additionally, final
		State from 26.9:			measurements apply
		1) severity, recovery			Correct functioning
		2) energization value, duty and contact load			
		3) see also <b>24.3</b>			
		1) operate and release value			
		+ 7) details of monitoring			
		(Damp heat)			None, but final
		State from 26.9:			measurements apply
		1) severity, recovery and, for immediate final measurement after the last cycle of <b>26.6</b>			Minimum value(s) of insulation resistance
		state from 22.2:			
		1) terminals			
		+ 2) measurement voltage			
		+ 3) time to reading	-		A 1 1:4: 11 C 1
		(Cold) State from 26.9:			Additionally, final measurements apply
		1) severity, recovery			measurements apply
		5) method			
		6) operating test requirements, as follows:			
		Categories I, II and III: refer to and state			Allowed number of failures.
		contacts from 41.3.2:			criteria of failure
		7) energization value			
		8) speed and duty factor			
		+ 9) protective devices			
		+ 10) checking equipment			
		11) load			
		Category 0: refer to, and state from 41.5.2:			Maximum contact circuit
		contact(s) to be tested			resistance
		1) energization value			
		3) speed and duty factor			
		and from <b>23.2</b> :			
		+ 1) frequency of test voltage			
		3) details of dynamic test			
		5) point of measurement			
		6) test current			
		7) open-circuit voltage	1		A 1 1::: 11 (* 1
		(Low pressure)			Additionally, final measurements apply
		State from 26.9: 1) severity, recovery			No breakdown, no flashover
		8) test voltage, duration of voltage test			
		+ Intermediate measurements:	1		Intermediate measurements:
		State all conditions and the part(s) of the climatic			state required results
		sequence to which they apply			_
40	Salt mist (D)	R State from <b>33.1.4</b> :	S 2		None, but final
Ì		1) duration			measurements apply
		2) recovery		<u> </u>	
41	Robustness of	M 35.2 Test No. 23	S 2		None, but final
	terminals (D) for pull,				measurements apply
49	bend and twist	R State from 37.4:	C O	-	Mothod 1.
42	Shock (D)	R State from 37.4: 1) method	S 2		Method 1: + opening and closing times
		2) pulse shape and acceleration			Both methods: final
		3) mounting			measurements apply
		4) monitoring details			
		5) energization value(s)			
		× Method 1-test and or rated			
		× contact load			
Symbo	ols and circled numbers, see	e Clauses 12 and 13.			1
	,				

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 ${\bf Table\ V-Test\ schedule\ 3\ Quality\ conformance\ inspection\ requirements}$ 

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements	
43	Bump (D)	R State from 38.4:  1) method 2) acceleration and number 3) mounting + 4) monitoring details 5) energization value(s), × Method 1-test and/or rated × contact load	S 2		Method 1: + opening and closing times Both methods: final measurements	
44	Vibration (D)	R State from 39.3: 1) vibration parameters 2) energization values, test and rated 3) mounting 4) monitoring details 5) contact load	S 2		+ opening and closing times Additionally, final measurements apply	
45	Acceleration (D)	R State from 40.4:  1) method 2) acceleration + duration 3) mounting 4) monitoring details 5) energization value(s) × Method 1-test and/or rated × contact load	S 2		Method 1: + opening and closing times Additionally final measurements apply	
	Final measurements	State the appropriate conditions and performance re above, from the following:	equirements still applicable to the tests			
46	— visual inspection, general	State from 17.7:  + 3) visual conditions properties to be checked a) marking and identification b) correct housing + 4) shaking of the relay + 5) physical properties, × surface	Same AQL as for the test above		<ul> <li>a) present and legible</li> <li>b) condition to be satisfactory</li> <li>4) no audible noise<sup>a</sup></li> <li>5) state details of results:</li> <li>× no mechanical deterioration</li> <li>× no peeling or chipping</li> </ul>	
	<ul><li>visual inspection, corrosion</li></ul>	+ State particular conditions unless self-evident			No evidence of corrosion which might impair operation	
	— d.c. coil resistance	19.1.3 Test No. (3)			Resistance limit(s) of the coil(s)	
	— insulation resistance	22.2 Test No. (16)			Minimum value(s) of insulation resistance	
	— contact-circuit resistance	23.2 Test No. (2)			Maximum contact-circuit resistance	
	other final     measurements  and circled numbers, see	+ State all conditions			State required results	

<sup>a</sup> Except that due to the normal structure

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 ${\bf Table\ V-Test\ schedule\ 3\ Quality\ conformance\ inspection\ requirements}$ 

Test No.	Examination or test	Conditions of test Refer to clause or sub-clause of IEC Publication 255-7	IL	AQL	Performance requirements			
	Sub-group C6	IL: S 2						
	For all tests in this sub-gro	oup AQL: 1.5 2.5 6	6.5					
	This sub-group contains de	estructive tests as marked by a (D)						
47	Thermal resistance	R State from 28.3: 1) mounting 2) energization values of operative range	S 2		Limits of thermal resistance			
		<ul><li>× 3) temperature coefficient</li><li>+ 4) evaluation procedure</li><li>+ 6) contact load</li></ul>						
48	Rapid change of temperature (D), Method 1	R State from 30.3: 2) temperatures, duration + 3) contact load	S 2		None, but final measurements apply			
49	Soldering: Test 2 (D)	R State from 36.4: 1) method	S 2		None, but final measurements apply			
50	Mould growth (D)	R State from 34.3: 1) all information required in IEC Publication 68-2-10 Clause 8, Items a) to g)			State all required results			
51	Final measurements	Test No. 46						
Symb	Symbols and circled numbers, see Clauses 12 and 13.							

 ${\bf Table\ VI-Test\ schedule\ 3\ Qualification\ approval\ procedure\ requirements}$ 

Examination or test  Qualification approval procedure	Refer to clause or sub-clause of IEC		· , ,	A 11 a1
Qualification approval procedure	Publication 255-7	Description in Table I	Sample size	Allowed defectives
	1	For	symbols see	Clause 12
Requirements				
Standard conditions for testing				
Applicable to all tests unless otherwise s	specified			
	16	Page 23		
All samples			I.	
Minimum sample size 24 specimens				
Visual inspection, excluding dimensions	17	M Sub moun AO/A2		
Visual inspection, excluding dimensions Dielectric test	20	M Sub-group A0/A3 M Sub-group A0	•••	•••
Dielectric test Contact-circuit resistance		0 1	•••	•••
	23	M Sub-group A0	•••	•••
D.C. coil resistance	19.1	M Sub-group A0	•••	•••
Functional test	24	M Sub-group A0		
Sealing	31.2	M Sub-group A0	•••	•••
	01.2	M Sub-group Ao	•••	•••
Sample group 1				
Minimum sample size 5 + 1 specimens				
Internal moisture	32	M Sub-group A1		
Coil impedance	19.3	M Sub-group A1		
Magnetic remanence	<b>54</b> and <b>25</b>	ℜ Sub-group B2		
Contact sticking	<b>53</b> and <b>25</b>	₿ Sub-group B3		
Γiming test	25	M Sub-group A1		
Mechanical tests	18.1	R Sub-group A1		
Insulation resistance	22	M Sub-group A4		
Γhermal e.m.f.	51	R Sub-group C5		
Robustness of terminals	35	M Sub-group C5		
Shock	37	R Sub-group C5		
Bump	38	R Sub-group C5	•••	
Vibration	39	R Sub-group C5		
Acceleration	40	R Sub-group C5		
Final measurements, as applicable				
— visual inspection	17	× Sub-group C5		
- d.c. coil resistance	19.1	× Sub-group C5		
d.e. con resistance	10.1	- Bub group Co	Same criter	ria as for
— insulation resistance	22	× Sub-group C5	the test a	
— contact-circuit resistance	23	× Sub-group C5		
— other final measurements	Conditions as for	+ Results as for		
	Sub-group C5	Sub-group C5		
Sample group 2	<u> </u>			
Minimum sample size 5 + 1 specimens				
Symbols and circled numbers, see Claus	10 110			

 ${\bf Table~VI-Test~schedule~3~Qualification~approval~procedure~requirements}$ 

Table VI — Test schedule 5	requirements of test			
Examination or test	Refer to clause or sub-clause of IEC Publication 255-7	Description in Table I	Sample size	Allowed defectives
Coldonability Test 1	36.3	M Cub man Do		
Solderability, Test 1	30.3	M Sub-group B2	•••	•••
Rapid change of temperature, Method 2	30	M Sub-group B2	•••	•••
Coil inductance	19.2	R Sub-group C2		
Thermal endurance	43 and 24	R Sub-group C5	•••	•••
Damp heat	27 and 22	R Sub-group C5	•••	•••
Climatic sequence	26 and 22	R Sub-group C5	•••	•••
Salt mist	33.1	R Sub-group C5	•••	•••
	33.1	in Sub-group Co	•••	•••
Final measurements, if still applicable		a 1 a=		
— visual inspection	17	× Sub-group C5		
— d.c. coil resistance	19.1	× Sub-group C5		
	22	C 1 CF	Same criter	
— insulation resistance	22	× Sub-group C5	the test a	above
— contact-circuit resistance	23	× Sub-group C5		
— other final measurements	Conditions as for	+ Results as for Sub-group C5		
	Sub-group C5	Sub-group Co		
Sample group 3				
Minimum sample size 5 + 1 specimens				
Check of dimensions	17.1	M Sub-group A2	•••	
Weighing	18.2	R Sub-group C3	•••	
Contact noise	50	R Sub-group C3	•••	
Electrical endurance	41	M Sub-group C4	•••	
Mechanical endurance	42	M Sub-group C4		
Final measurements, as applicable				
— visual inspection	17	× Sub-group C4		
— insulation resistance	22	× Sub-group C4	Same criter	ia as for
— contact-circuit resistance	23	× Sub-group C4	the test a	above
— other final measurements	Conditions as for	Conditions as for + Results as for		
	Sub-group C4	Sub-group C4		
Sample group 4				
Minimum sample size 5 + 1 specimens				
Thermal resistance	28	R Sub-group C6		•••
Temperature rise	29	R Sub-group B2		
Rapid change of temperature,	30	R Sub-group C6	•••	•••
Method 1		. 5		
Soldering. Test 2	36.3	R Sub-group C6		
Mould growth	34	R Sub-group C6		
Final measurements, as applicable				<u> </u>
— visual inspection	17	× Sub-group C6		
— d.c. coil resistance	19.1	× Sub-group C6	G	
— insulation resistance	22	× Sub-group C6	Same criter	
— contact-circuit resistance	23	× Sub-group C6	the test a	anove
— other final measurements	Conditions as for	+ Results as for		
	Sub-group C6	Sub-group C6		
Symbols and circled number, see Clauses	12 and 13.	<u>I</u>	ı	
, , , , , , , , , , , , , , , , , , , ,				

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